

Tae Jung Kim

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/1828348/publications.pdf>

Version: 2024-02-01

66
papers

528
citations

687363

13
h-index

752698

20
g-index

66
all docs

66
docs citations

66
times ranked

735
citing authors

#	ARTICLE	IF	CITATIONS
19	A Parametric Model for Temperature Dependence of Dielectric Function of AlSb Film. Journal of Nanoscience and Nanotechnology, 2019, 19, 6801-6807.	0.9	0
20	Dielectric Functions and Critical Points of GaAsSb Alloys. Journal of the Korean Physical Society, 2019, 74, 595-599.	0.7	3
21	Parameterized optical properties of monolayer MoSe ₂ . AIP Advances, 2019, 9, .	1.3	3
22	Sub-microsecond response time deep-ultraviolet photodetectors using In-Ga ₂ O ₃ thin films grown via low-temperature atomic layer deposition. Journal of Alloys and Compounds, 2019, 780, 400-407.	5.5	52
23	Temperature Dependence of the Dielectric Function of Monolayer MoSe ₂ . Scientific Reports, 2018, 8, 3173.	3.3	13
24	Pt/Alumina Hyperbolic Metafilms with High-Temperature Stability, Wide Wavelength Tunability, and Omnidirectional Absorption. Physica Status Solidi (A) Applications and Materials Science, 2018, 215, 1800287.	1.8	9
25	Temperature Dependence of the Dielectric Response and Critical Point Energies of Bi _{1.85} Gd _{0.15} Te ₃ . Journal of Nanoscience and Nanotechnology, 2018, 18, 6321-6325.	0.9	0
26	Optical characterization of the PtSi/Si by using spectroscopic ellipsometry. Journal of the Korean Physical Society, 2016, 69, 291-296.	0.7	0
27	Temperature dependence of the critical points of monolayer MoS ₂ by ellipsometry. Applied Spectroscopy Reviews, 2016, 51, 621-635.	6.7	27
28	Parameterization of the dielectric function of In _x Al _{1-x} As alloys as a function of composition. Current Applied Physics, 2015, 15, S30-S34.	2.4	5
29	Analytic representation of the dielectric function of GaN for temperatures from 26 to 690 K. Journal of the Korean Physical Society, 2014, 65, 733-738.	0.7	2
30	Ellipsometric study of the temperature dependences of the dielectric function and the critical points of AlSb at temperatures from 300 to 803 K. Journal of the Korean Physical Society, 2014, 65, 515-519.	0.7	1
31	Analytic determination of the dielectric function of InSb at energies from 0.74 to 6.42 eV at temperatures from 31 to 675 K. Journal of the Korean Physical Society, 2014, 64, 1872-1877.	0.7	1
32	Temperature dependent dielectric function and the ϵ_2 critical points of hexagonal GaN from 30 to 690 K. AIP Advances, 2014, 4, .	1.3	7
33	Reinforcement of Interfacial Adhesion of a Coated Polymer Layer on a Cobalt-Chromium Surface for Drug-Eluting Stents. Langmuir, 2014, 30, 8020-8028.	3.5	20
34	Effect of post-annealing temperature on the dielectric function of solution-processed LaAlO ₃ /Si Films. Journal of the Korean Physical Society, 2014, 64, 1509-1513.	0.7	0
35	Parameterization of the dielectric functions of InGaSb alloys. Current Applied Physics, 2014, 14, 768-771.	2.4	2
36	Influences of rapid thermal process on solution-deposited Ti-silicate/Si films: Phase segregation, composition and interface changes, and dielectric properties. Materials Chemistry and Physics, 2014, 145, 168-175.	4.0	6

#	ARTICLE	IF	CITATIONS
37	Interband transitions and dielectric functions of InGaSb alloys. Applied Physics Letters, 2013, 102, .	3.3	6
38	Application of rapid thermal process to solution-processed Ti-silicate films for enhancing permittivity without losing amorphous nature. Current Applied Physics, 2013, 13, S41-S44.	2.4	2
39	Optical properties of AlAs _x Sb _{1-x} alloys determined by in situ ellipsometry. Applied Physics Letters, 2013, 103, 011901.	3.3	4
40	Optical properties of solution-processed LaAlO _x /Si films using spectroscopic ellipsometry. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2013, 31, 04D110.	1.2	3
41	Temperature dependence of the dielectric functions and the critical points of InSb by spectroscopic ellipsometry from 31 to 675 K. Journal of Applied Physics, 2013, 114, .	2.5	15
42	Temperature-dependent optical properties of epitaxial CdO thin films determined by spectroscopic ellipsometry and Raman scattering. Journal of Applied Physics, 2013, 113, 183515.	2.5	11
43	Stability of UV exposed RR-P3BT films by spectroscopic ellipsometry. , 2013, , .		0
44	Parameterization of the dielectric function of InP from 1.19 to 6.57 eV for temperatures from 25 to 700 K. Journal of Applied Physics, 2012, 112, .	2.5	6
45	Investigation of the Dielectric Function of Solution-Processed InGaZnO Films Using Ellipsometry. Journal of Nanoscience and Nanotechnology, 2012, 12, 5804-5807.	0.9	1
46	Parametric modeling of the dielectric function and identification of the critical point of a CdMgTe alloy in the vacuum ultraviolet spectral range. Journal of the Korean Physical Society, 2012, 60, 1219-1223.	0.7	0
47	Parametric model dielectric functions of InAs for temperatures from 22 to 675 K. Journal of the Korean Physical Society, 2012, 61, 1821-1825.	0.7	4
48	Investigation of InSb critical-point energies at 25 K by using spectroscopic ellipsometry. Journal of the Korean Physical Society, 2012, 61, 439-443.	0.7	1
49	Dielectric function and energy of the E ₀ critical point of hexagonal GaN at 26 K studied by using spectroscopic ellipsometry. Journal of the Korean Physical Society, 2012, 61, 791-794.	0.7	2
50	Temperature dependence of the dielectric function and critical-point energies of InAs. Journal of the Korean Physical Society, 2012, 61, 97-101.	0.7	6
51	Investigation of the Crystallization of Amorphous Si by Imaging Ellipsometry. Journal of Nanoscience and Nanotechnology, 2011, 11, 6198-6202.	0.9	0
52	Temperature dependence of the dielectric response of AlSb. , 2011, , .		1
53	Optical study of sol-gel processed ZrO ₂ /Si films by spectroscopic ellipsometry. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2011, 29, 04D108.	1.2	7
54	Effect of the Ga Ratio on the Dielectric Function of Solution-processed InGaZnO Films. Journal of the Korean Physical Society, 2011, 59, 3396-3400.	0.7	4

#	ARTICLE	IF	CITATIONS
55	In-situ study of molecular dynamics in a water environment by using imaging ellipsometry. <i>Advances in Natural Sciences: Nanoscience and Nanotechnology</i> , 2010, 1, 045003.	1.5	0
56	Dielectric functions and interband transitions of $\text{In}_{1-x}\text{Al}_x\text{Sb}$ alloys. <i>Applied Physics Letters</i> , 2010, 97, .	3.3	6
57	InAs critical-point energies at 22 K from spectroscopic ellipsometry. <i>Applied Physics Letters</i> , 2010, 97, 171912.	3.3	21
58	Interband transitions of $\text{InAs}_x\text{Sb}_{1-x}$ alloy films. <i>Applied Physics Letters</i> , 2009, 95, 111902.	3.3	24
59	Imaging of Collapsed Fatty Acid Films at Air-Water Interfaces. <i>Langmuir</i> , 2009, 25, 9262-9269.	3.5	22
60	Characterization of Si nanorods by spectroscopic ellipsometry with efficient theoretical modeling. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2008, 205, 876-879.	1.8	31
61	Overlayer effects in the critical-point analysis of ellipsometric spectra: Application to $\text{In}_x\text{Ga}_{1-x}\text{As}$ alloys. <i>Journal of Applied Physics</i> , 2008, 103, .	2.5	4
62	Model dielectric functions for $\text{Al}_x\text{Ga}_{1-x}\text{As}$ alloys of arbitrary compositions. <i>Journal of Applied Physics</i> , 2008, 104, 013515.	2.5	13
63	Direct Imaging of a Collapsed Langmuir Monolayer and Multilayer Formation. <i>Journal of the Korean Physical Society</i> , 2008, 53, 1488-1491.	0.7	1
64	Optical Properties of GaN by Using Ellipsometry and a Band Calculation. <i>Journal of the Korean Physical Society</i> , 2008, 53, 1575-1579.	0.7	10
65	Dielectric Functions of CdSe and ZnSe Obtained by Using Vacuum Ultra-Violet Spectroscopic Ellipsometry. <i>Journal of the Korean Physical Society</i> , 2007, 50, 806.	0.7	6
66	Dielectric functions of $\text{In}_x\text{Ga}_{1-x}\text{As}$ alloys. <i>Physical Review B</i> , 2003, 68, .	3.2	43